

Spectral Imaging

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Reflectance spectroscopy & spectral imaging

- Spectral imaging is an efficient way of collecting reflectance spectra
- Spectral imaging collects many reflectance spectra simultaneously usually at a lower spectral resolution than reflectance spectroscopy (high spectral resolution)
- Multispectral image small number of spectral bands (low spectral resolution)
- Hyperspectral imaging large number of spectral bands (medium spectral resolution)



- Fibre optic reflectance spectrometer (FORS) collects one spectrum at a time
- Spectral reflectance is the percentage of light reflected back from a sample
- Spectral imaging can be used for imaging irradiance (emission), transmittance and reflectance

Spectral imaging = multispectral + hyperspectral imaging

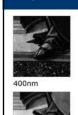


Overview

- What is spectral imaging?
- What can we learn from spectral imaging?
- · Different types of spectral imaging devices
- Instrument specification considerations
- Calibration & post-processing an important step in quantitative spectral imaging
- Material identification using spectral reflectance
- The Big Data challenge & modern statistical methods for information extraction – automated uncovering of any 'hidden' features
- Combination with other non-invasive techniques a systematic approach to non-invasive investigation



Spectral imaging





640nm





680nm



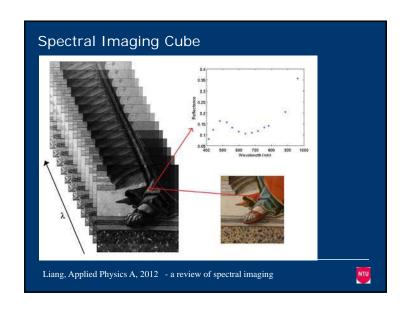


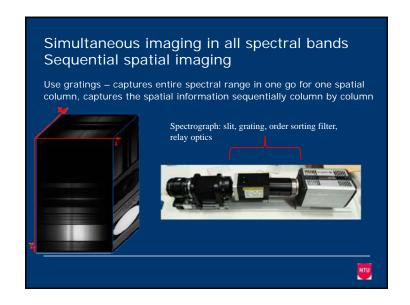


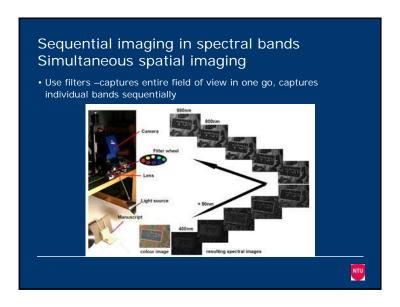


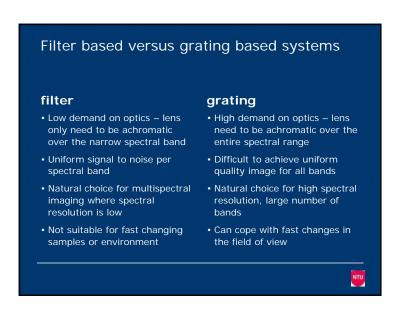
760nm

Liang et al. Journal of Imaging Science & Technology, 2005



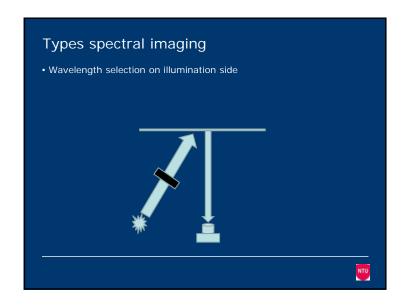


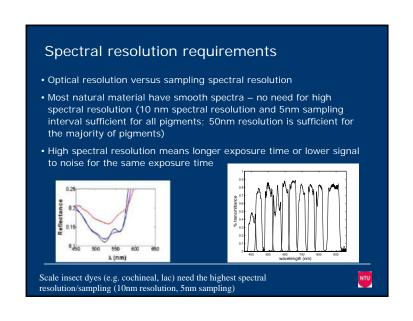












Spatial resolution

- Optical resolution (real resolution) versus sampling resolution
- High number of pixels means high sampling resolution but not the actual resolution! You need good optics (lens) to achieve high resolution and high image quality
- Required resolution depends on application, e.g. 25-50 microns gives high enough image quality for imaging of brush strokes



What information can we get through different wavelength range?

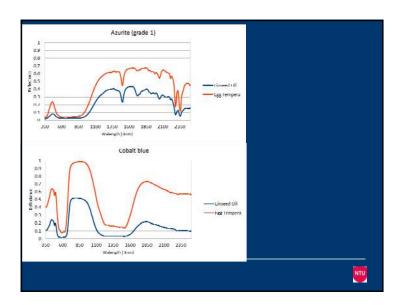
- UV/VIS/NIR (~350-1000nm): characteristic spectral feature of the pigments
- SWIR (1000–2500 nm): additional spectral features for some pigments (e.g. azurite, cobalt containing pigments), information on the binding medium, detection of moisture
- MWIR/LWIR (FTIR range): identification of molecular bonds

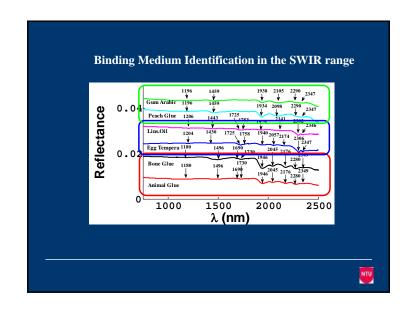


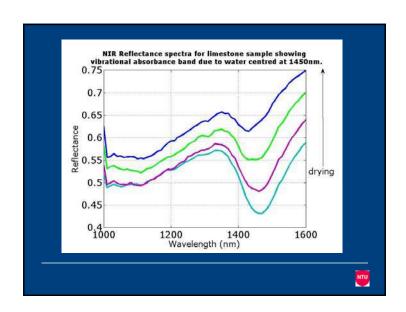
Spectral range

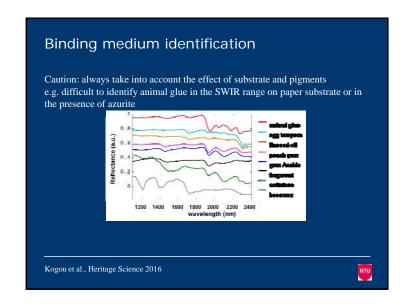
- UV/VIS/NIR: ~350nm to ~1000nm, Si CCD based detector
- SWIR: 1000 nm 2500 nm, InGaAs, MCT or InSb detectors
- MWIR: 3000 nm 5000 nm, InSb detectors
- LWIR (FTIR range): 7 14 microns, MCT detectors

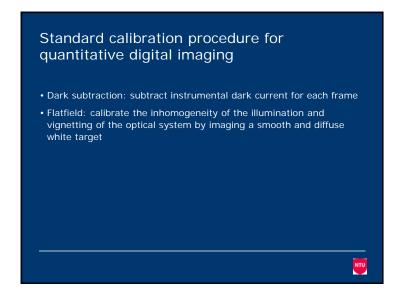












Dark current

- Semi-conductor detector at a non-zero temperature will be subject
 to thermal agitation which can eject valence electrons into the
 conduction band which is then collected and read out, i.e. electrons
 are readout in the absence of photon illumination
- These charges can accumulate over time => dark current increases with 'exposure time'
- It is temperature dependent => cooling of CCDs are very important
- CCDs can be cooled by thermal electric methods to -20 to -100 degrees C



Spectral calibration of filter based systems

 Spectral calibration: image a standard spectral white target through each filter

Note:

For pigment identification, we only need good spectral calibration, but for accurate colour imaging we need the full absolute calibration

For monitoring spectral change, relative calibration is sufficient, i.e. relative position of target, illumination and detector is fixed.



Linearity of a CCD

- CCDs are highly linear in intensity compared with older technology such as photographic plates (linear means increasing the intensity by x times will result in the detector registers x times the number of counts)
- Close to saturation CCDs can deviate from linearity (high quality CCDs are made such that saturation level occurs before deviation from linearity)
- Small deviation from linearity can occur close to zero photon exposure



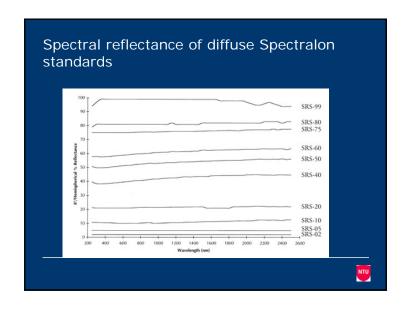
Calibration standards for imaging reflected light

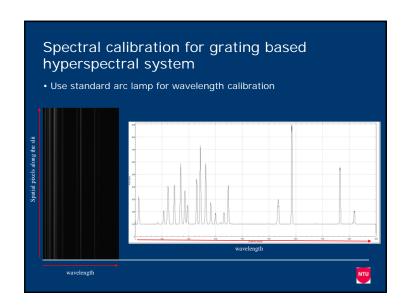
- Spectral standards
- white standard with known spectral reflectance over a broad spectral range usually covering the visible/NIR spectral range



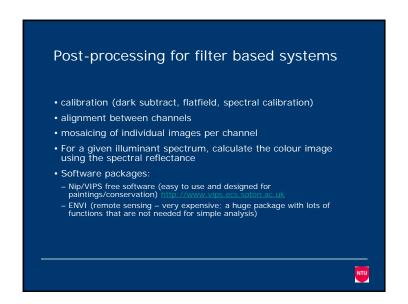
 Matt white chart (larger than the field of view) for flatfield calibration to correct for spatial inhomogeneity of illumination, vignetting of optical system (spatial inhomogeneity of optical throughput), pixel-to-pixel gain variation of the CCD

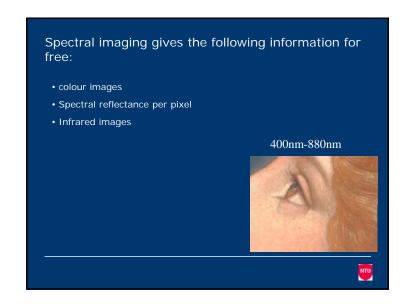




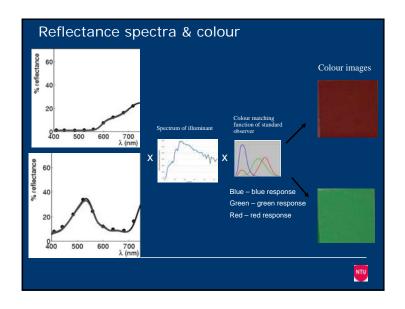


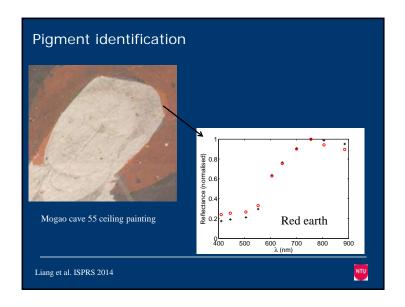
Calculating spectral reflectance Calibrated image final object frame> =(<object frame> - <dark frame>)/<normalised dark subtracted flatfield frame> where <normalised dark subtracted flatfield frame> =<dark subtracted flatfield frame>/mean(<dark subtracted flatfield frame>) Reflectance image per channel =(<final object frame>/t_obj) / (mean(<final spectral white frame>)/t_white) Where <final spectral white frame> is calibrated in the same way as <final object frame>, t_obj and t_white are the exposure times for the object and spectral white standard frames, the mean should be taken from the central areas of the spectral white image if the field of view is larger than the spectral white standard itself

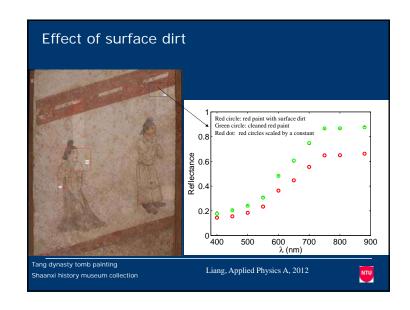


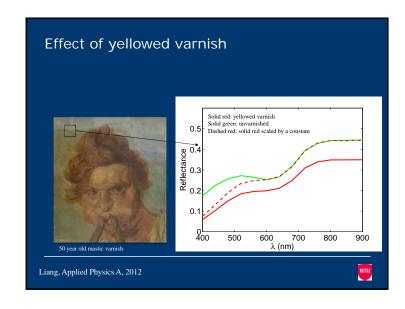


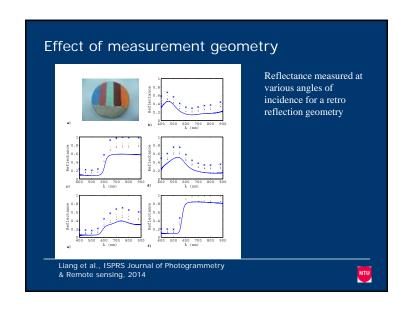


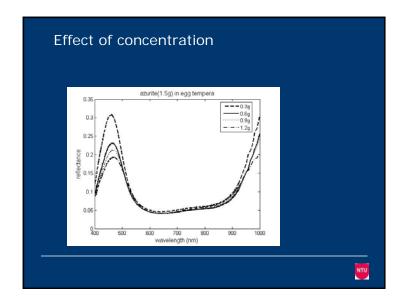


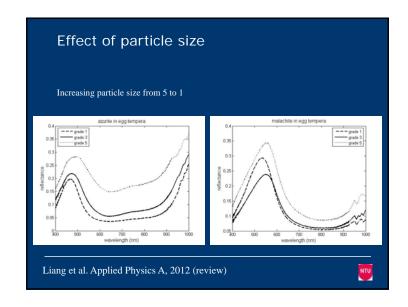


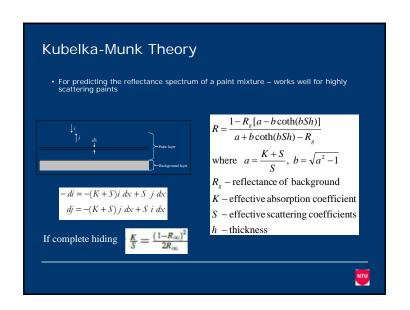


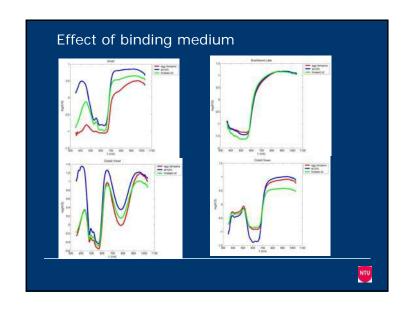












Identification of pigment mixtures

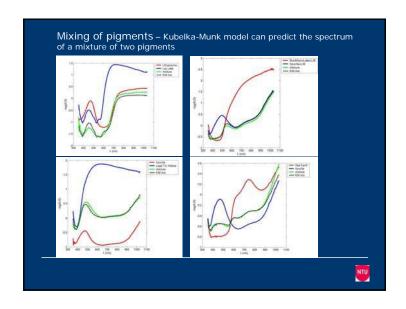
• It is possible to identify pigment mixtures using the spectral reflectance data and an algorithm that finds the concentrations c_1 and c_2 that gives the best fit to an unknown spectrum. The algorithm finds the combination of pigments that gives the best best fit spectrum. An educated guess as a starting point helps.

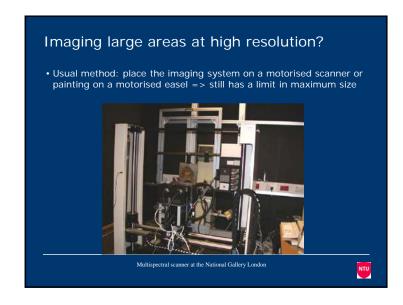
$$\left(\frac{K}{S}\right)_{tot} = c_1 \left(\frac{K}{S}\right)_1 + c_2 \left(\frac{K}{S}\right)_2 + \cdots$$

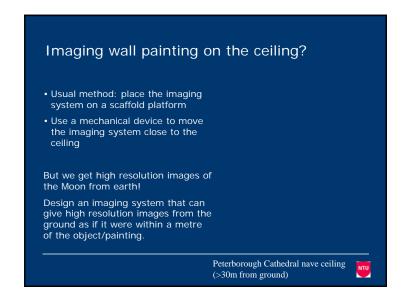
- Reflectance can be calculated from K/S
- Works best for highly scattering pigments, not so well for transparent and absorbing pigments

Liang, Applied Physics A, 2012



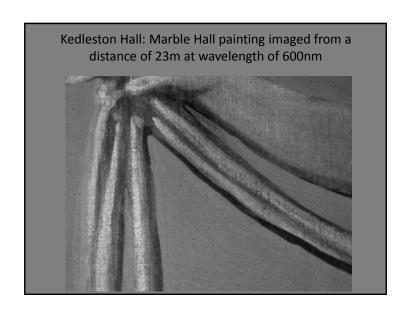






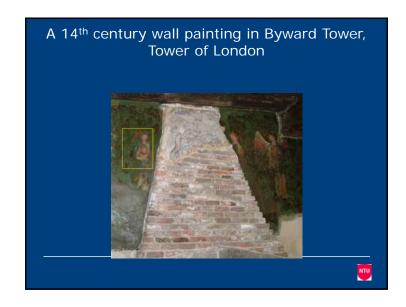


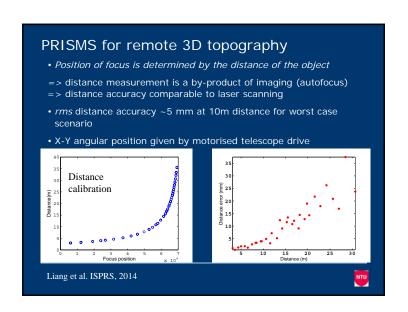






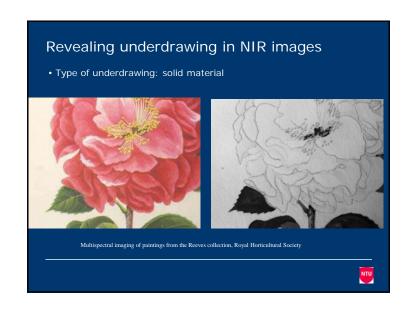




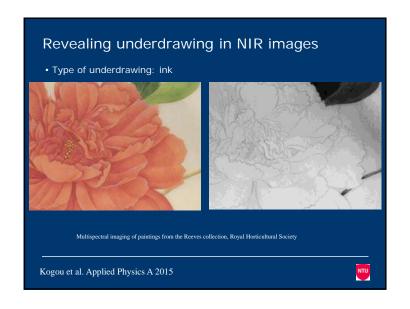


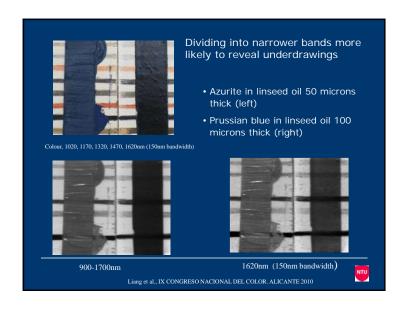


PRISMS: 3D spectral imaging all in one instrument Remote imaging – high resolution (-80 micron at 10m) imaging without scaffolding Close range imaging of small objects Fully automated capture & data processing Efficient in collecting spectral reflectance data Pigment identification Interband comparison to identify areas of alteration Reveal underdrawings and faded writings Accurate colour rendering under any illumination Colour and 3D topography are by-products of spectral imaging => you get them for free!

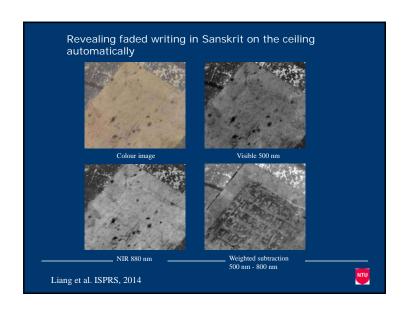


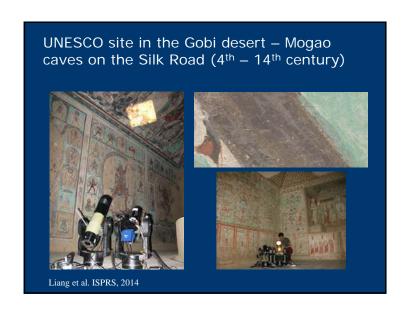


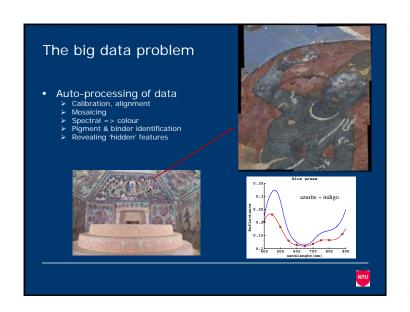


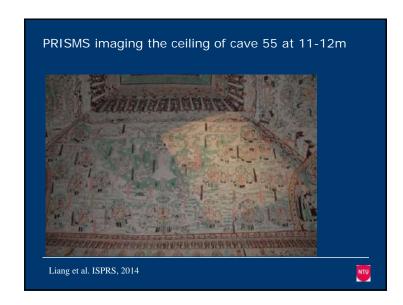






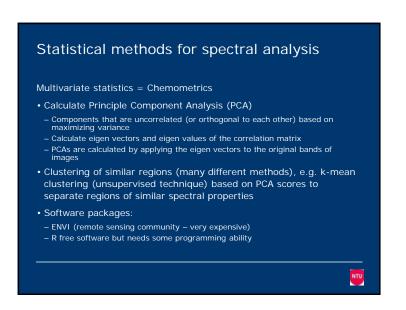


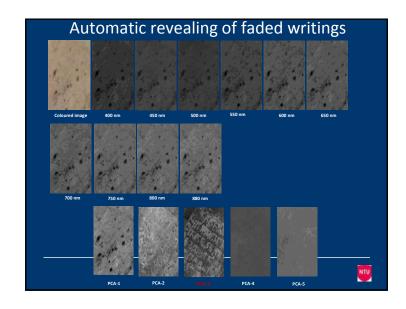


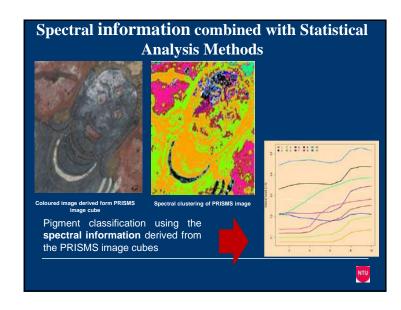




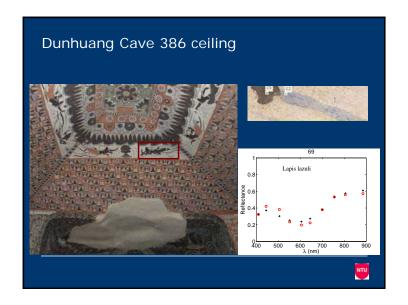


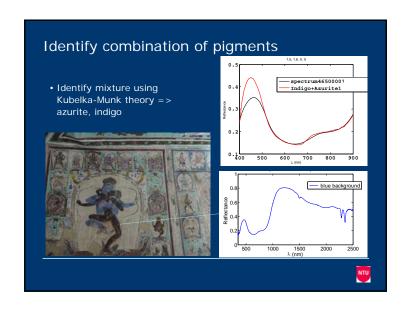


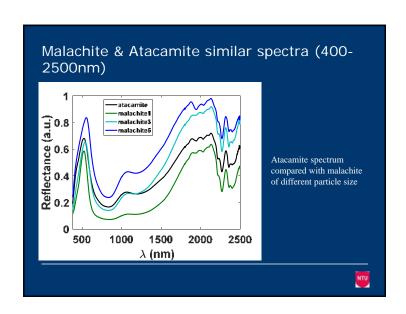


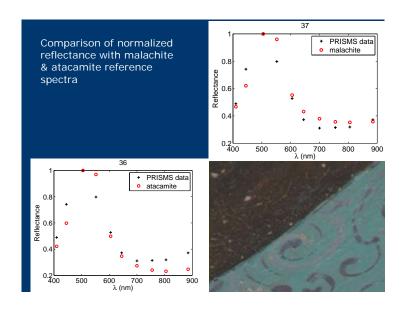


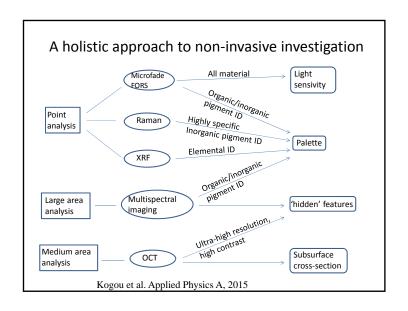










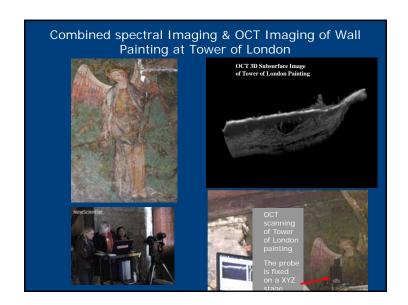


There is no Best techniques

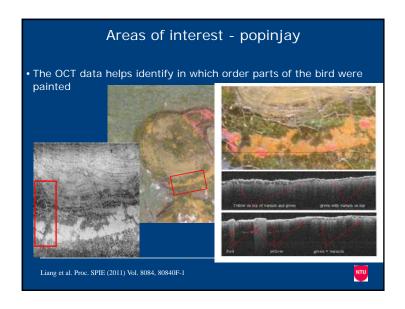
There are only complementary techniques One technique cannot solve all problems

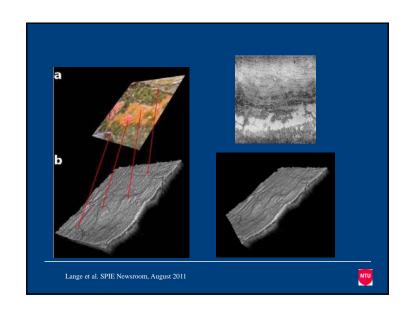
Technique	Working distance (mm)	Spatial resolution or spot size (mm)	Field of view or scanned size (mm)	Spectral range
Micro-Raman	~0.5	~0.002	~0.002	532 nm, 638 nm excitation, Raman shift range 150-3800 cm ⁻¹
XRF	~1	~0.2	~0.2	2-50 keV
Microfade	~30	~0.46×0.76	~0.46×0.76	400-700 nm
VIS-NIR FORS	~30	~0.5	~0.5	400-950 nm
SWIR FORS	~2	~5	~ 5	900-2400 nm
UV-VIS-NIR spectral imaging	2240	~0.085	~115×85	400-900 nm
ост	~10	~0.009×0.009× 0.0045	~10 (width)	930 nm (100 nm bandwidth)

Kogou et al. Applied Physics A, 2015

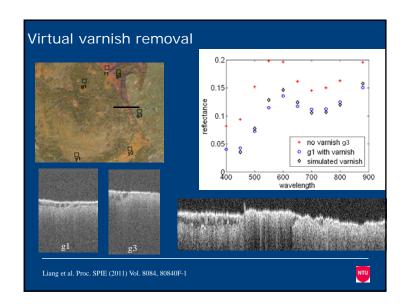


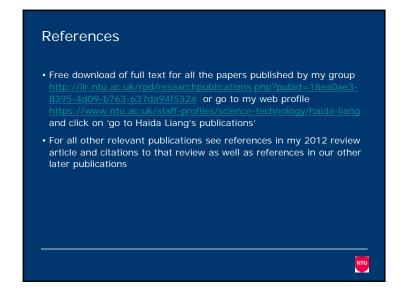
Watercolour — an example (blueish region) Raman: azurite, malachite, goethite, unidentified blue crystal XRF: : Cu (Fe, Co, Pb, As) ((Mn, K, Ca)) FORS: smalt, azurite, malachite = > blue paint is a mixture of smalt, azurite, malachite (goethite is impurity of malachite) **Tolour image derived from multispectral image, Chinese export painting, V&A collection Kogou et al. Applied Physics A, 2015











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- The National Gallery (London): John Cupitt, David Saunders, Helen Howard & colleagues
- Victoria & Albert Museum: Lucia Burgio, Kate Bailey
- Royal Horticultural Society: Charlotte Brooks & colleagues
- Gooch & Housego plc: Chris Pannell, Jon Ward and colleagues
- Dunhuang Academy: Su Bomin and colleagues
- Shaanxi History Museum: Zhang Qunxi and colleagues
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